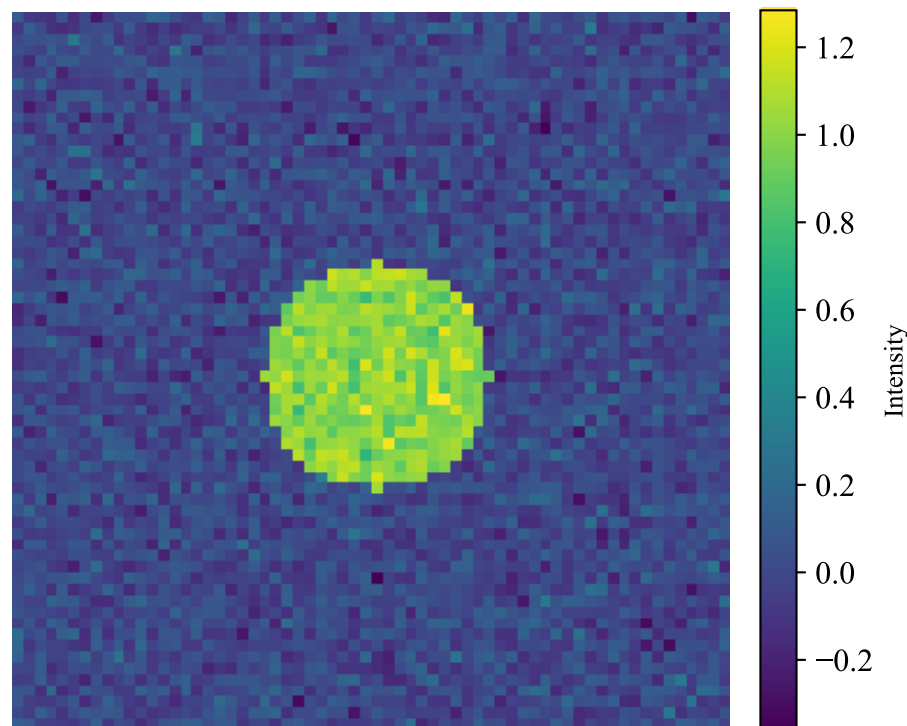
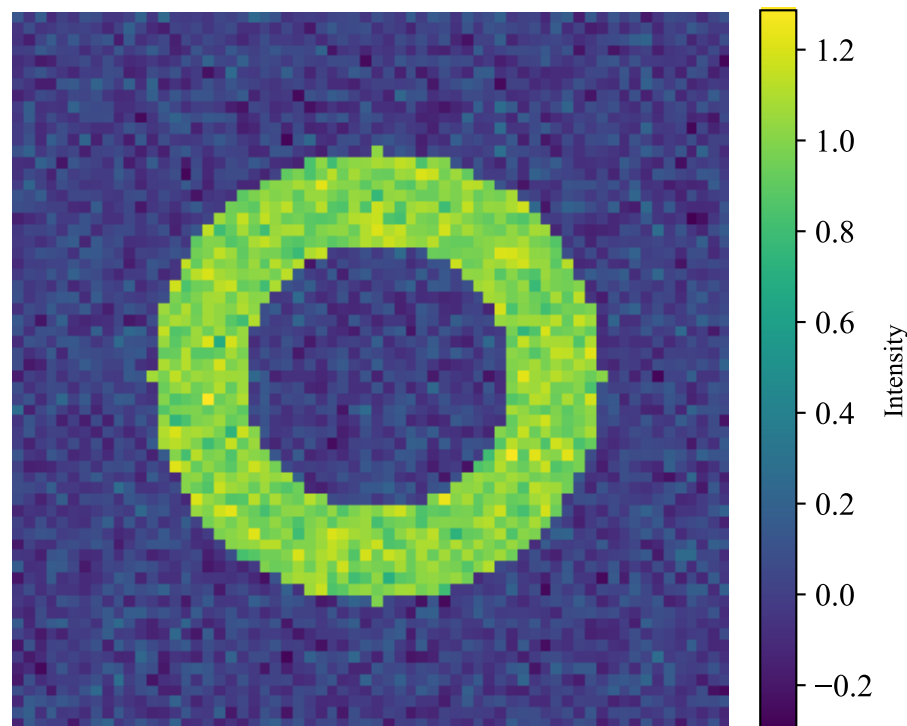


Representative Wafer Map Patterns for Each Defect Type

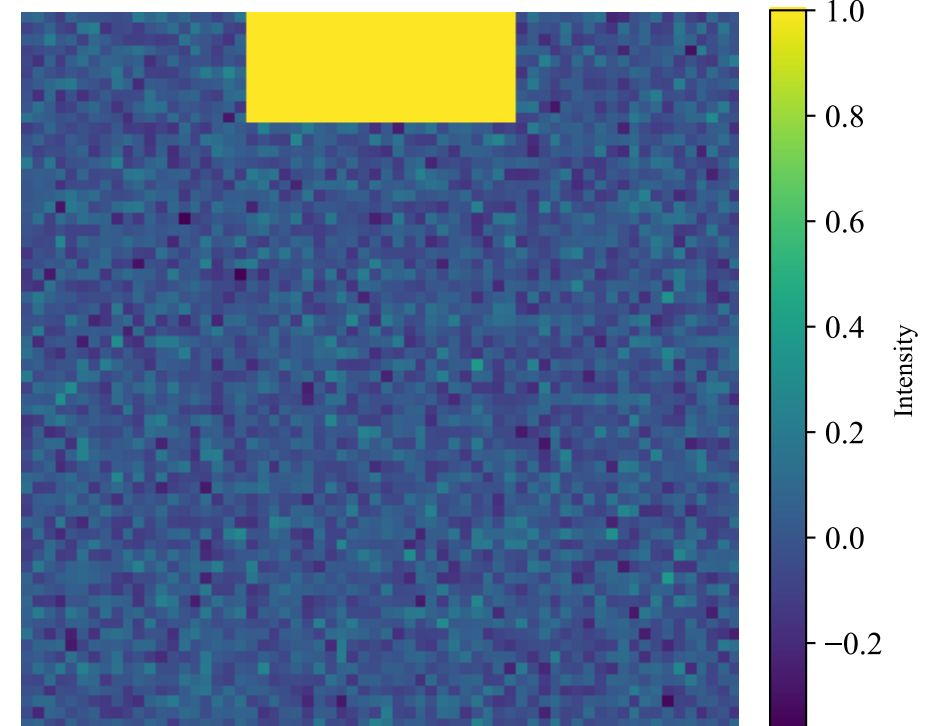
(a) Center



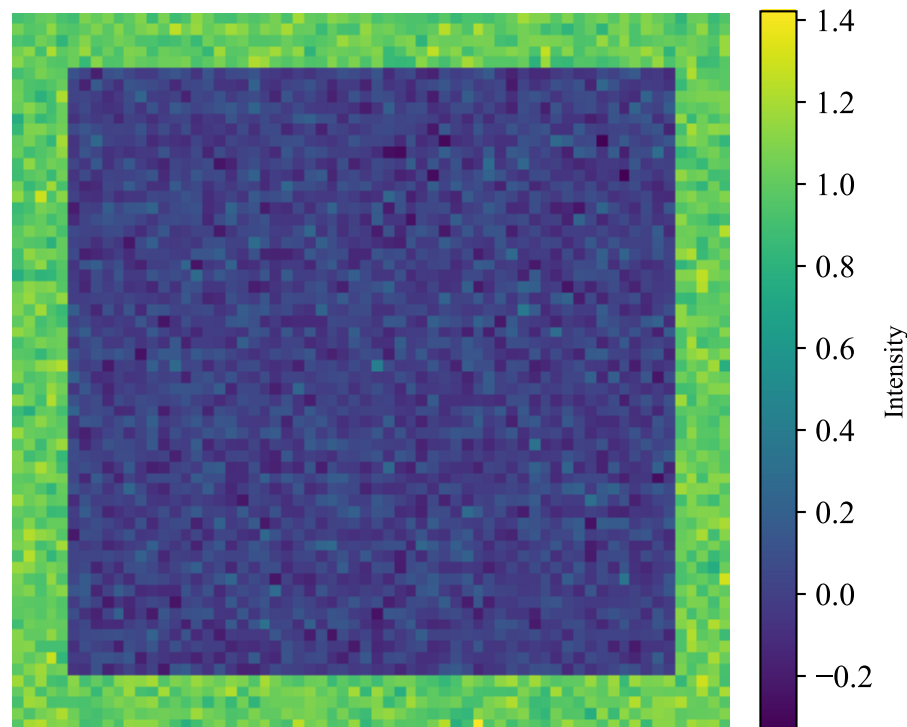
(b) Donut



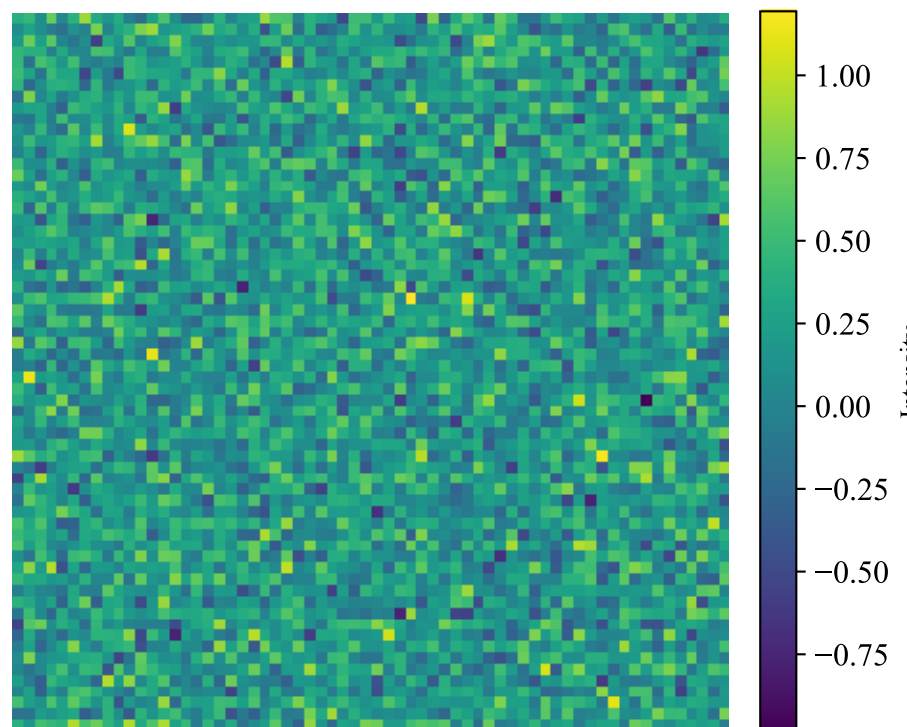
(c) Edge-Loc



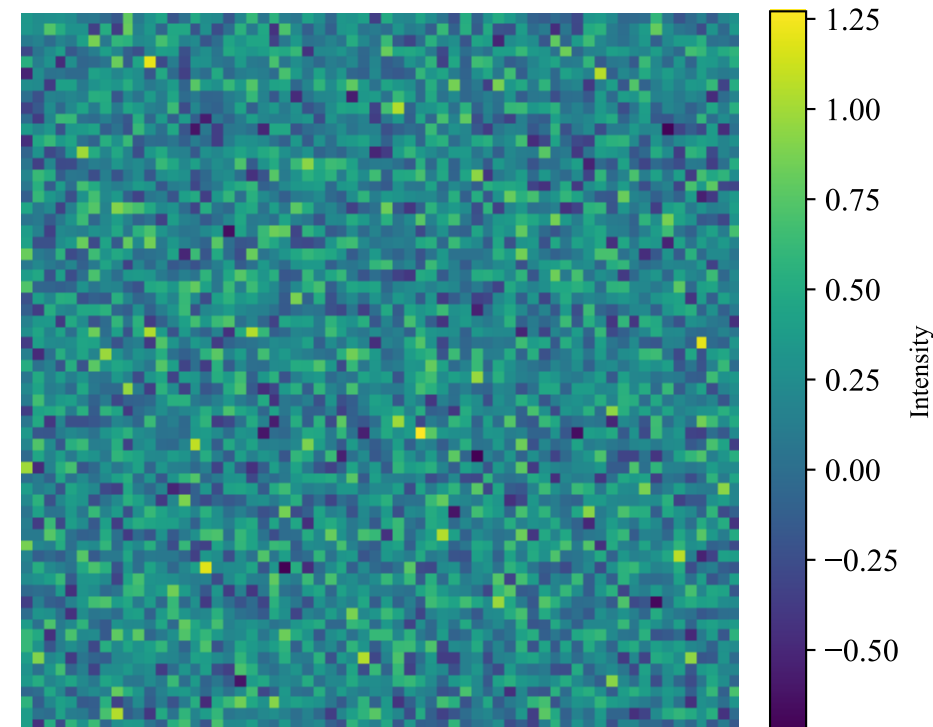
(d) Edge-Ring



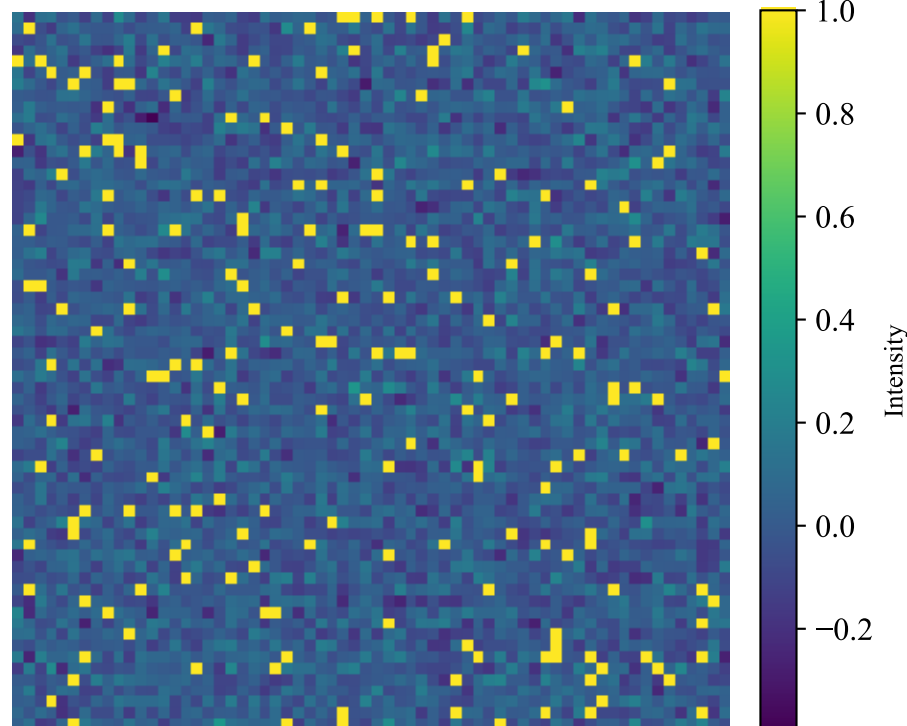
(e) Loc



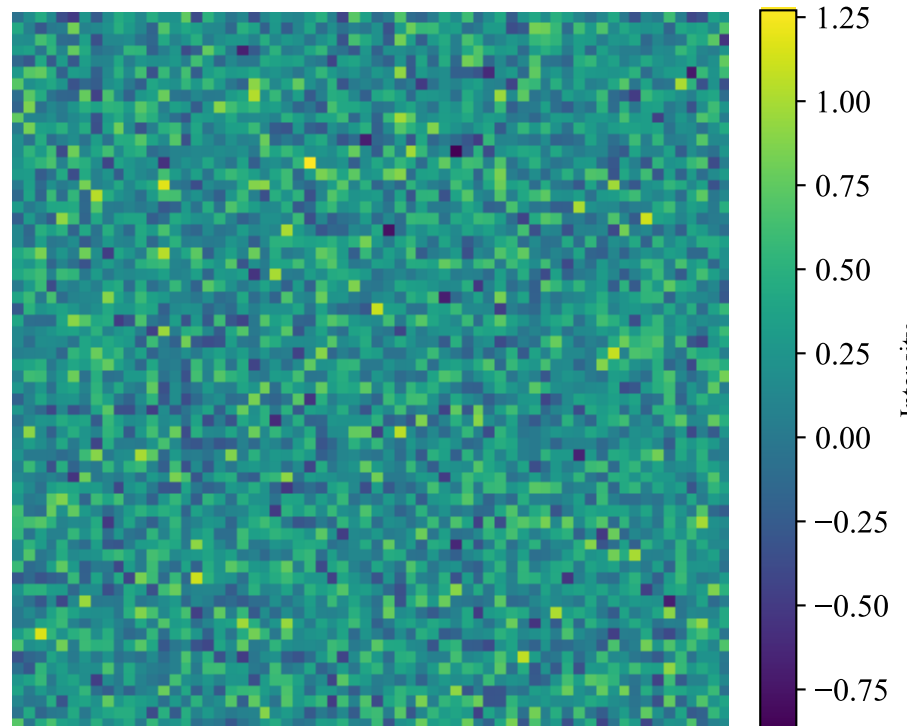
(f) Near-full



(g) Random



(h) Scratch



(i) none

